

# Product Specification

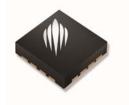
# PE42521

UltraCMOS<sup>®</sup> SPDT RF Switch 9 kHz - 13 GHz

# Features

- HaRP<sup>™</sup> technology enhanced
  - Fast settling time of 2 μs
  - No gate and phase lag
  - No drift in insertion loss and phase
- Fast switching time of 500 ns
- High power handling @ 4 GHz in  $50\Omega$ 
  - 36 dBm CW
  - 38.5 dBm instantaneous power
  - 26 dBm terminated port
- High linearity
  - 65 dBm IIP3
- Low insertion loss
  - 0.75 dB @ 3 GHz
  - 1.15 dB @ 10 GHz
- 1.85 dB @ 13 GHz
- High isolation
  - 44 dB @ 3 GHz
  - 30 dB @ 10 GHz
  - 17 dB @ 13 GHz
- ESD performance
  - 3kV HBM on RF pins to GND
  - 1.5kV HBM on all pins
  - 1kV CDM on all pins

### Figure 2. Package Type 16-lead 3x3 mm QFN

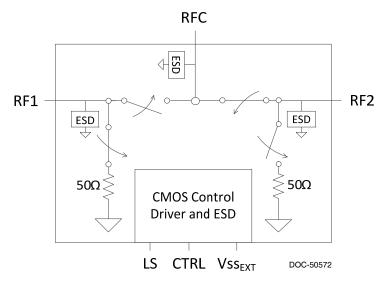


# Product Description

The PE42521 SPDT absorptive RF switch is designed for use in Test/ATE and other high performance wireless applications. This broadband general purpose switch maintains excellent RF performance and linearity from 9 kHz through 13 GHz. This switch is a pin-compatible upgraded version of PE42552 with fast switching time and higher power handling of 36 dBm continuous wave (CW) and 38.5 dBm instantaneous power in 50 $\Omega$  @ 4 GHz. The PE42521 exhibits high isolation, fast settling time, and is offered in a 3x3 mm QFN package.

The PE42521 is manufactured on Peregrine's UltraCMOS<sup>®</sup> process, a patented variation of silicon-oninsulator (SOI) technology on a sapphire substrate, offering the performance of GaAs with the economy and integration of conventional CMOS.

# Figure 1. Functional Diagram





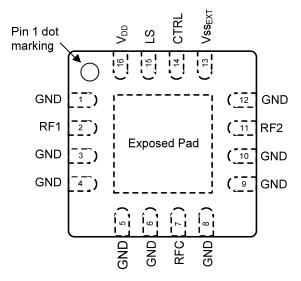
# Table 1. Electrical Specifications @ 25°C, $V_{DD}$ = 3.3V, $Vss_{EXT}$ = 0V or $V_{DD}$ = 3.4V, $Vss_{EXT}$ = -3.4V, ( $Z_s = Z_L = 50\Omega$ ) unless otherwise noted

Parameter	Path	Condition	Min	Тур	Мах	Unit
Operation frequency			9 kHz		13 GHz	As shown
Insertion loss	RFC-RFX	9 kHz – 10 MHz 10 MHz – 3 GHz 3 GHz – 7.5 GHz 7.5 GHz – 10 GHz 10 GHz – 12 GHz 12 GHz – 13 GHz		0.60 0.75 0.95 1.15 1.75 1.85	0.80 1.00 1.20 1.40 2.20 2.60	dB dB dB dB dB dB
Isolation	RFX-RFX	9 kHz – 10 MHz 10 MHz – 3 GHz 3 GHz – 7.5 GHz 7.5 GHz – 10 GHz 10 GHz – 12 GHz 12 GHz – 13 GHz	70 46 35 23 16 14	90 49 37 26 19 17		dB dB dB dB dB dB
Isolation	RFC-RFX	9 kHz – 10 MHz 10 MHz – 3 GHz 3 GHz – 7.5 GHz 7.5 GHz – 10 GHz 10 GHz – 12 GHz 12 GHz – 13 GHz	80 42 39 26 18 14	90 44 41 30 21 17		dB dB dB dB dB dB
Return loss (active port)	RFC-RFX	9 kHz – 10 MHz 10 MHz – 3 GHz 3 GHz – 7.5 GHz 7.5 GHz – 10 GHz 10 GHz – 12 GHz 12 GHz – 13 GHz		23 19 16 21 10 15		dB dB dB dB dB dB
Return loss (common port)	RFC-RFX	9 kHz – 10 MHz 10 MHz – 3 GHz 3 GHz – 7.5 GHz 7.5 GHz – 10 GHz 10 GHz – 12 GHz 12 GHz – 13 GHz		23 19 16 21 10 16		dB dB dB dB dB dB
Return loss (terminated port)	RFX	9 kHz – 10 MHz 10 MHz – 3 GHz 3 GHz – 7.5 GHz 7.5 GHz – 10 GHz 10 GHz – 12 GHz 12 GHz – 13 GHz		32 23 18 11 6 5		dB dB dB dB dB dB
Input 0.1 dB compression point <sup>1</sup>	RFC-RFX	600 MHz – 13 GHz		Fig. 5		dBm
Input IP2	RFC-RFX	834 MHz, 1950 MHz		120		dBm
Input IP3	RFC-RFX	834 MHz, 1950 MHz, and 2700 MHz		65		dBm
Settling time		50% CTRL to 0.05 dB final value		2	4	μs
Switching time		50% CTRL to 90% or 10% of final value		500	700	ns

Note 1: The input 0.1 dB compression point is a linearity figure of merit. Refer to Table 3 for the RF input power  $P_{IN}$  (50 $\Omega$ )



# Figure 3. Pin Configuration (Top View)



#### **Table 2. Pin Descriptions**

Pin #	Pin Name	Description
2	RF1 <sup>1</sup>	RF port 1
1, 3, 4, 5, 6, 8, 9, 10, 12	GND	Ground
7	RFC <sup>1</sup>	RF common
11	RF2 <sup>1</sup>	RF port 2
13	Vss <sub>EXT</sub> <sup>2</sup>	External Vss negative voltage control
14	CTRL	Digital control logic input
15	LS	Logic Select - used to determine the definition for the CTRL pin (see <i>Table 5</i> )
16	V <sub>DD</sub>	Supply voltage
Pad	GND	Exposed pad: ground for proper operation

Notes: 1. RF pins 2, 7, and 11 must be at 0V DC. The RF pins do not require DC blocking capacitors for proper operation if the 0V DC requirement is met

2. Use Vss<sub>EXT</sub> (pin 13) to bypass and disable internal negative voltage generator. Connect Vss<sub>EXT</sub> (pin 13) to GND (Vss<sub>EXT</sub> = 0V) to enable internal negative voltage generator

#### **Table 3. Operating Ranges**

Parameter	Symbol	Min	Тур	Max	Unit
Supply voltage (normal mode, Vss <sub>EXT</sub> = 0V) <sup>1</sup>	$V_{\text{DD}}$	2.3		5.5	v
Supply voltage (bypass mode, $Vss_{EXT} = -3.4V$ , $V_{DD} \ge 3.4V$ for full spec. compliance) <sup>2</sup>	V <sub>DD</sub>	2.7	3.4	5.5	V
Negative supply voltage (bypass mode) <sup>2</sup>	Vss <sub>EXT</sub>	-3.6		-3.2	V
Supply current (normal mode, Vss <sub>EXT</sub> = 0V) <sup>1</sup>	I <sub>DD</sub>		120	200	μA
Supply current (bypass mode, Vss <sub>EXT</sub> = -3.4V) <sup>2</sup>	I <sub>DD</sub>		50	80	μA
Negative supply current (bypass mode, $Vss_{EXT} = -3.4V)^2$	I <sub>SS</sub>	-40	-16		μA
Digital input high (CTRL)	V <sub>IH</sub>	1.17		3.6	v
Digital input low (CTRL)	VIL	-0.3		0.6	v
Digital input current	I <sub>CTRL</sub>			10	μA
$\begin{array}{l} \mbox{RF input power, CW} \\ \mbox{(RFC-RFX)}^3 \\ \mbox{9 kHz} \leq 600 \mbox{ MHz} \\ \mbox{600 MHz} \leq 4 \mbox{ GHz} \\ \mbox{4 GHz} \leq 13 \mbox{ GHz} \end{array}$	P <sub>IN-CW</sub>			Fig. 4 36 Fig. 5	dBm dBm dBm
$\begin{array}{l} \text{RF input power, pulsed} \\ (\text{RFC-RFX})^4 \\ 9 \text{ kHz} \leq 600 \text{ MHz} \\ 600 \text{ MHz} \leq 13 \text{ GHz} \end{array}$	P <sub>IN-PULSED</sub>			Fig. 4 Fig. 5	dBm dBm
$ \begin{array}{l} \text{RF input power, hot} \\ \text{switch, CW}^3 \\ 9 \text{ kHz} \leq 10 \text{ MHz} \\ 10 \text{ MHz} \leq 13 \text{ GHz} \end{array} $	P <sub>IN-HOT</sub>			<i>Fig. 4</i> 20	dBm dBm
$ \begin{array}{l} \text{RF input power into} \\ \text{terminated ports, CW} \\ \left(\text{RFX}\right)^{3} \\ & 9 \text{ kHz} \leq 30 \text{ MHz} \\ & 30 \text{ MHz} \leq 13 \text{ GHz} \end{array} $	P <sub>IN,TERM</sub>			Fig. 4 26	dBm dBm
Operating temperature range	T <sub>OP</sub>	-40	+25	+85	°C

Notes: 1. Normal mode: connect Vss<sub>EXT</sub> (pin 13) to GND (Vss<sub>EXT</sub> = 0V) to

enable internal negative voltage generator

2. Bypass mode: use Vss<sub>EXT</sub> (pin 13) to bypass and disable internal negative voltage generator

3. 100% duty cycle, all bands,  $50\Omega$ 

4. Pulsed, 5% duty cycle of 4620 μs period, 50Ω



#### Table 4. Absolute Maximum Ratings

Parameter/Condition	Symbol	Min	Max	Unit
Supply voltage	V <sub>DD</sub>	-0.3	5.5	V
Digital input voltage (CTRL)	V <sub>CTRL</sub>	-0.3	3.6	V
LS input voltage	V <sub>LS</sub>	-0.3	3.6	V
$ \begin{array}{l} \mbox{RF input power, CW} \\ \mbox{(RFC-RFX)}^1 & 9 \ \mbox{kHz} \leq 600 \ \mbox{MHz} \\ \mbox{600 \ \mbox{MHz}} \leq 4 \ \mbox{GHz} \\ \mbox{4 \ \mbox{GHz}} \leq 13 \ \mbox{GHz} \end{array} $	P <sub>IN-CW</sub>		Fig. 4 36 Fig. 5	dBm dBm dBm
$ \begin{array}{l} \mbox{RF input power, pulsed} \\ \mbox{(RFC-RFX)}^2 \\ \mbox{9 kHz} \leq 600 \mbox{ MHz} \\ \mbox{600 MHz} \leq 13 \mbox{ GHz} \end{array} $	PIN-PULSED		Fig. 4 Fig. 5	dBm dBm
$\begin{array}{l} \text{RF input power into terminated} \\ \text{ports, CW (RFX)}^1 \\ & 9 \text{ kHz} \leq 30 \text{ MHz} \\ & 30 \text{ MHz} \leq 13 \text{ GHz} \end{array}$	PIN,TERM		Fig. 4 26	dBm dBm
Storage temperature range	T <sub>ST</sub>	-65	+150	°C
ESD voltage HBM <sup>3</sup> RF pins to GND All pins	V <sub>ESD,HBM</sub>		3000 1500	V V
ESD voltage MM <sup>4</sup> , all pins	$V_{\text{ESD,MM}}$		200	V
ESD voltage CDM <sup>5</sup> , all pins	V <sub>ESD,CDM</sub>		1000	V

Notes: 1. 100% duty cycle, all bands,  $50\Omega$ 

2. Pulsed, 5% duty cycle of 4620  $\mu s$  period, 50  $\Omega$ 

3. Human Body Model (MIL-STD 883 Method 3015)

4. Machine Model (JEDEC JESD22-A115)

5. Charged Device Model (JEDEC JESD22-C101)

Exceeding absolute maximum ratings may cause permanent damage. Operation should be restricted to the limits in the Operating Ranges table. Operation between operating range maximum and absolute maximum for extended periods may reduce reliability.

### **Electrostatic Discharge (ESD) Precautions**

When handling this UltraCMOS<sup>®</sup> device, observe the same precautions that you would use with other ESD-sensitive devices. Although this device contains circuitry to protect it from damage due to ESD, precautions should be taken to avoid exceeding the rating specified.

#### Latch-Up Avoidance

Unlike conventional CMOS devices, UltraCMOS<sup>®</sup> devices are immune to latch-up.

#### Switching Frequency

The PE42521 has a maximum 25 kHz switching rate when the internal negative voltage generator is used (pin 13 = GND). The rate at which the PE42521 can be switched is only limited to the switching time (*Table 1*) if an external negative supply is provided (pin 13 = Vss<sub>EXT</sub>).

Switching frequency describes the time duration between switching events. Switching time is the time duration between the point the control signal reaches 50% of the final value and the point the output signal reaches within 10% or 90% of its target value.

#### **Optional External Vss Control (Vss<sub>EXT</sub>)**

For proper operation, the  $Vss_{EXT}$  control pin must be grounded or tied to the Vss voltage specified in *Table 3*. When the  $Vss_{EXT}$  control pin is grounded, FETs in the switch are biased with an internal negative voltage generator. For applications that require the lowest possible spur performance,  $Vss_{EXT}$  can be applied externally to bypass the internal negative voltage generator.

#### **Spurious Performance**

The typical spurious performance of the PE42521 is -152 dBm when  $Vss_{EXT} = 0V$  (pin 13 = GND). If further improvement is desired, the internal negative voltage generator can be disabled by setting  $Vss_{EXT} = -3.4V$ .

#### Table 5. Control Logic Truth Table

LS	CTRL	RFC-RF1	RFC-RF2
0	0	off	on
0	1	on	off
1	0	on	off
1	1	off	on

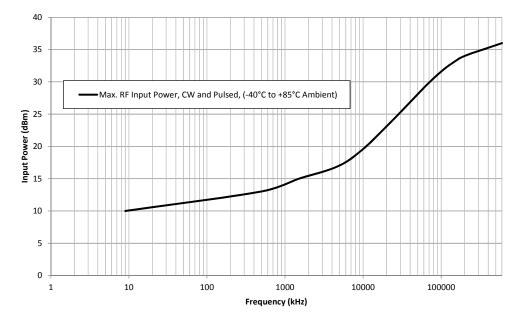
#### **Moisture Sensitivity Level**

The Moisture Sensitivity Level rating for the PE42521 in the 16-lead 3x3 mm QFN package is MSL3.

#### Logic Select (LS)

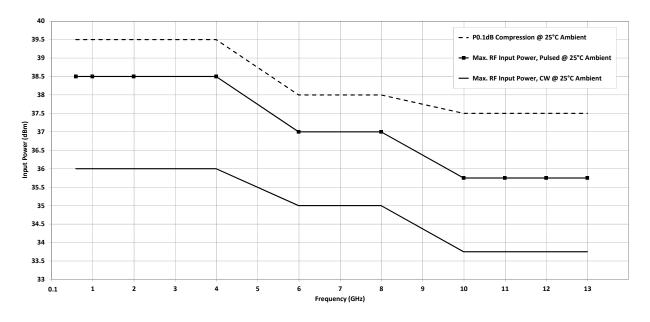
The Logic Select feature is used to determine the definition for the CTRL pin.





# Figure 4. Power De-rating Curve for 9 kHz – 600 MHz (50Ω)





# Figure 5a. Power De-rating Curve for 600 MHz – 13 GHz @ 25°C Ambient (50Ω)

Figure 5b. Power De-rating Curve for 600 MHz – 13 GHz @ 85°C Ambient (50Ω)

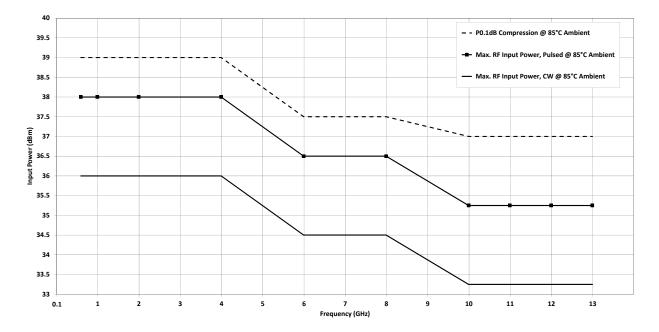
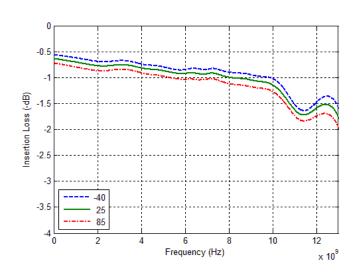




Figure 6. Insertion Loss vs. Temp (RFC-RF1)

Figure 7. Insertion Loss vs. V<sub>DD</sub> (RFC–RF1)

0



-0.5 -1 Insertion Loss (-dB) -1.5 -2 -2.5 -3 2.3 -3.5 3.4 5.5 -4 12 0 2 10 4 6 Frequency (Hz) x 10<sup>9</sup>

Figure 8. Insertion Loss vs. Temp (RFC-RF2)

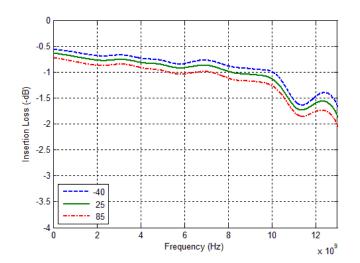
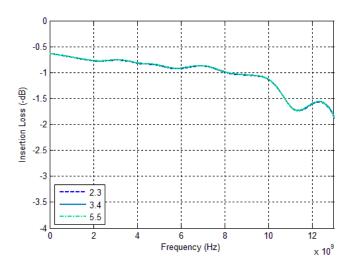
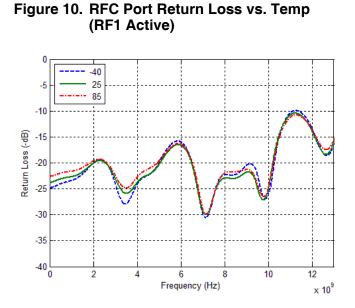


Figure 9. Insertion Loss vs. V<sub>DD</sub> (RFC–RF2)







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Figure 12. RFC Port Return Loss vs. Temp (RF2 Active)

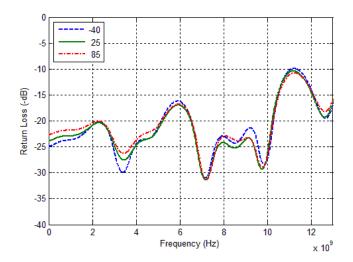


Figure 11. RFC Port Return Loss vs. V<sub>DD</sub> (RF1 Active)

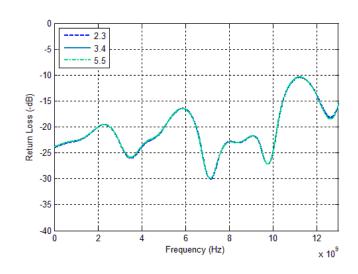


Figure 13. RFC Port Return Loss vs. V<sub>DD</sub> (RF2 Active)

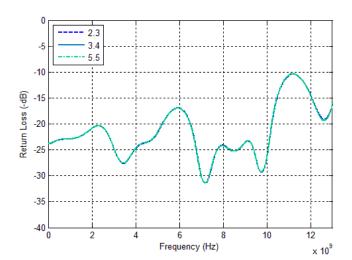




Figure 14. Active Port Return Loss vs. Temp (RF1 Active)

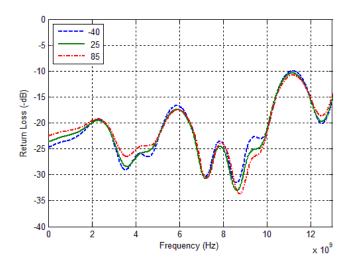


Figure 16. Active Port Return Loss vs. Temp (RF2 Active)

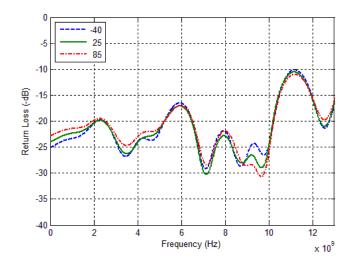


Figure 15. Active Port Return Loss vs. V<sub>DD</sub> (RF1 Active)

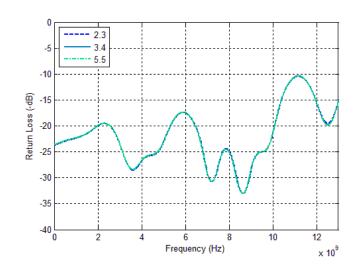
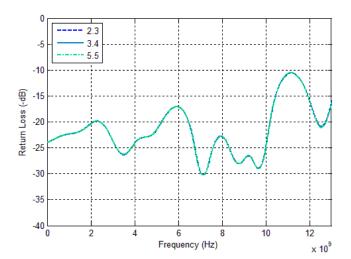


Figure 17. Active Port Return Loss vs. V<sub>DD</sub> (RF2 Active)





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# Typical Performance Data @ $25^{\circ}$ C and V<sub>DD</sub> = 3.4V unless otherwise specified

Figure 18. Terminated Port Return Loss vs. Temp (RF1 Active)

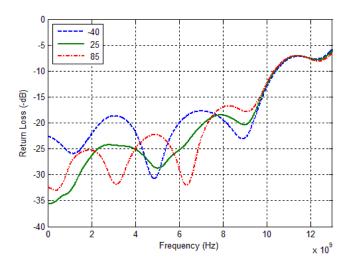


Figure 20. Terminated Port Return Loss vs. Temp (RF2 Active)

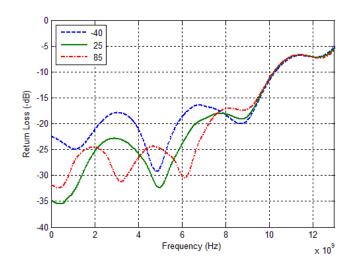


Figure 19. Terminated Port Return Loss vs. V<sub>DD</sub> (RF1 Active)

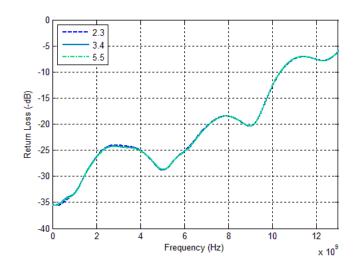
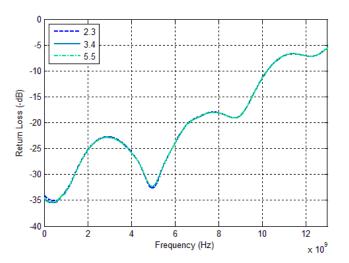
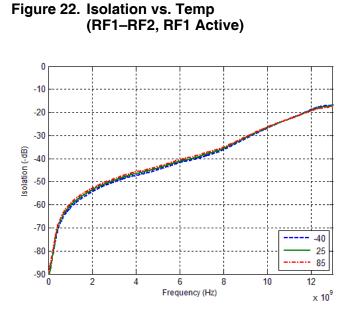


Figure 21. Terminated Port Return Loss vs. V<sub>DD</sub> (RF2 Active)







#### Figure 23. Isolation vs. V<sub>DD</sub> (RF1-RF2, RF1 Active) 0 -10 -20 -30 Isolation (-dB) -40 -50 -60 -70 2.3 -80 34 5.5 -90 10 12 0 2 4 6 8 Frequency (Hz) x 10<sup>9</sup>

Figure 24. Isolation vs. Temp (RF2–RF1, RF2 Active)

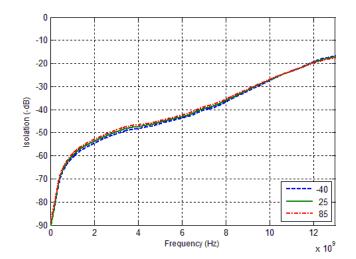
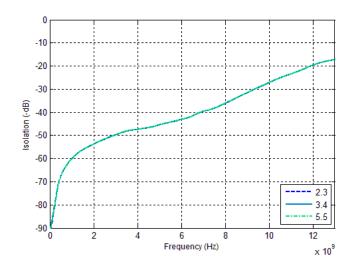
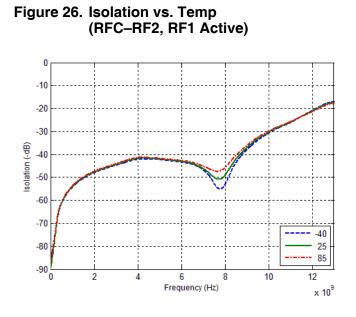


Figure 25. Isolation vs. V<sub>DD</sub> (RF2–RF1, RF2 Active)







#### Figure 27. Isolation vs. V<sub>DD</sub> (RFC–RF2, RF1 Active) 0 -10 -20 -30 Isolation (-dB) -40 -50 -60 -70 - 2.3 -80 3.4 5.5 -90 <mark>|\_</mark> 0 10 12 2 4 6 Frequency (Hz) x 10<sup>9</sup>

Figure 28. Isolation vs. Temp (RFC–RF1, RF2 Active)

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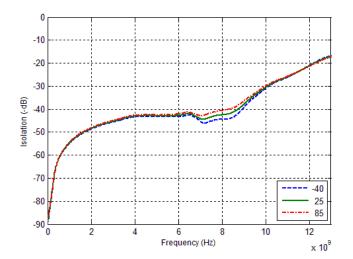
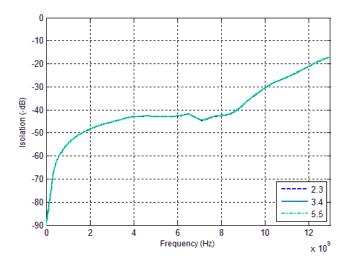


Figure 29. Isolation vs. V<sub>DD</sub> (RFC–RF1, RF2 Active)



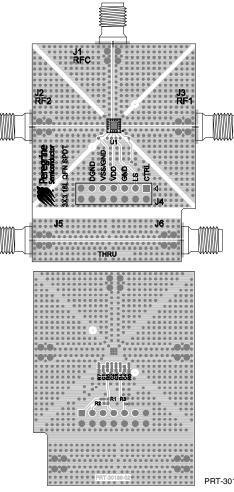


# **Evaluation Kit**

The SPDT switch evaluation board was designed to ease customer evaluation of Peregrine's PE42521. The RF common port is connected through a 50 $\Omega$  transmission line via the SMA connector, J1. RF1 and RF2 ports are connected through 50Ω transmission lines via SMA connectors J2 and J3, respectively. A 50Ω through transmission line is available via SMA connectors J5 and J6, which can be used to de-embed the loss of the PCB. J4 provides DC and digital inputs to the device.

For the true performance of the PE42521 to be realized, the PCB should be designed in such a way that RF transmission lines and sensitive DC I/O traces are heavily isolated from one another.

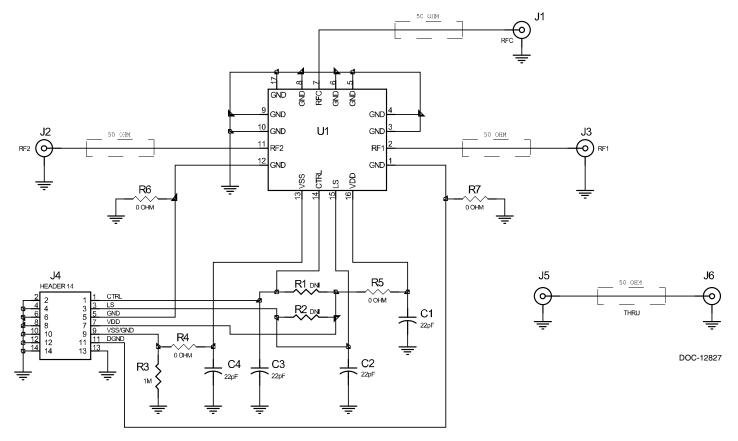
#### Figure 30. Evaluation Kit Layout



PBT-30186



# Figure 31. Evaluation Board Schematic



Notes: 1. Use PRT-30186-02 PCB 2. CAUTION: Contains parts and assemblies susceptible

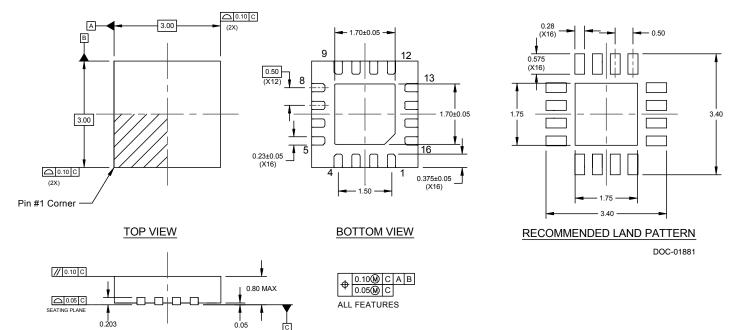
to damage by electrostatic discharge (ESD)



# Figure 32. Package Drawing

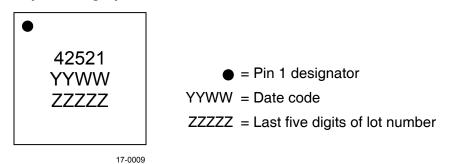
0.203

16-lead 3x3 mm QFN



#### Figure 33. Top Marking Specifications

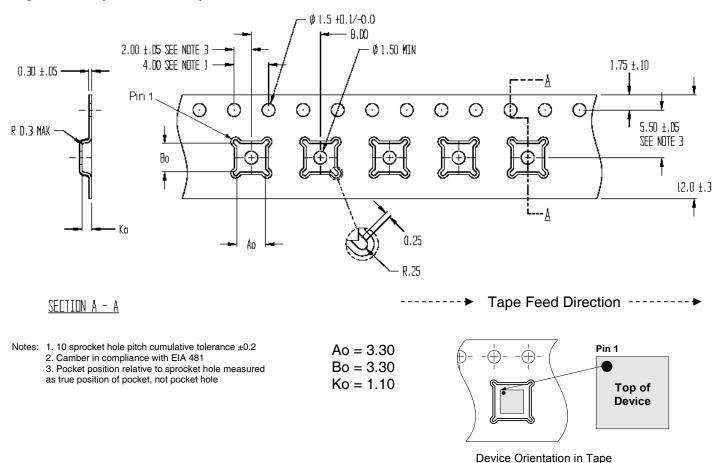
SIDE VIEW



c



#### Figure 34. Tape and Reel Specifications



#### **Table 6. Ordering Information**

Order Code	Description	Description Package	
PE42521MLBA-Z	PE42521 SPDT RF switch	Green 16-lead 3x3 mm QFN	3000 units / T&R
EK42521-02	PE42521 Evaluation kit	Evaluation kit	1 / Box

#### **Sales Contact and Information**

For sales and contact information please visit www.psemi.com.

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